



Metrics NA TC Chapter

Wednesday, April 14, 2021

Via Web Conference

2:00 PM–5:00 PM (Pacific Time)

AGENDA

	Time												
1 Welcome/Call to Order	2:00-2:05												
1.1 Introductions													
1.2 Required Meeting Elements (Membership Requirements, Antitrust and Intellectual Property Reminders, and Effective Meeting Guidelines)													
1.3 Agenda Review													
2 Review of Previous Meeting Minutes (including open Action Items review)	2:05-2:10												
3 Staff Report	2:10-2:25												
4 Liaison Reports	2:25-2:30												
4.1 Japan TC Chapter													
5 Ballot Review (including safety and IP checks)	2:30-4:00												
<table border="1"><thead><tr><th>#</th><th>When</th><th>TF</th><th>Details</th></tr></thead><tbody><tr><td>6467</td><td>Cycle 1-2021</td><td>ESD/ESC Task Force</td><td>Line Item Revision to SEMI E129-0912: Guide to Assess and Control Electrostatic Charge in a Semiconductor Manufacturing Facility</td></tr><tr><td>6468</td><td>Cycle 1-2021</td><td>ESD/ESC Task Force</td><td>Line Item Revision to SEMI E78-0912: Guide to Assess and Control Electrostatic Discharge (ESD) And Electrostatic Attraction (ESA) for Equipment</td></tr></tbody></table>		#	When	TF	Details	6467	Cycle 1-2021	ESD/ESC Task Force	Line Item Revision to SEMI E129-0912: Guide to Assess and Control Electrostatic Charge in a Semiconductor Manufacturing Facility	6468	Cycle 1-2021	ESD/ESC Task Force	Line Item Revision to SEMI E78-0912: Guide to Assess and Control Electrostatic Discharge (ESD) And Electrostatic Attraction (ESA) for Equipment
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6 Subcommittee & Task Force Reports													
6.1 ESD/ESC Task Force – Chuck McClain / Viraj Pandit	4:00-4:15												
6.2 EMC Task Force – Vladimir Kraz / Mark Frankfurth													
6.3 RF Measurements Task Force – Supika Mashiro													
6.4 Equipment RAMP Metrics Task Force – Paul Schneider / Todor Ganev													
6.5 Critical Chamber Components (CCC) Test Methods Task Force – Michael Cox / Supika Mashiro													



7 Old Business

4:15-4:20

- 7.1 Standards due for Five-Year Review
- 7.2 SNARFs approaching Three-Year Document Development Project Period

8 New Business

4:20-4:30

- 8.1 New TFOFs & SNARFs
- 8.2 New Ballot(s) Submission Summary

9 New Action Item Review

4:30-4:35

10 Next Meetings Schedule (TBD)

4:35-4:40

Date/Time/Location

- ESD/ESC Task Force
- EMC Task Force
- RF Measurements Task Force
- Equipment RAMP Metrics Task Force
- Critical Chamber Components (CCC) Test Methods Task Force

11 Adjournment

4:40

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